

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	22581	substrate and gate and ((gate adj oxide) or (gate adj insulator) or (gate adj insulating)) and (gate adj electrode)	USPAT	OR	ON	2004/12/21 15:10
S2	29	S1 and ((nitriding or carbonizing) with (sidewall or (side adj wall)))	USPAT	OR	ON	2004/12/17 19:11
S3	2	(metal with (gate adj electrode)) and (itriding or carbonizing) and ((side adj wall) or sidewall)	USPAT	OR	ON	2004/12/16 13:11
S4	2	((("6489236") or ("5966606")).PN.	USPAT	OR	OFF	2004/12/16 13:35
S5	281	gate and nitride and (tantalum or titanium) and (gate with (sidewall or (side adj wall)) with nitrid\$8) and ammonia	USPAT	OR	ON	2004/12/16 13:40
S6	457	gate and nitride and (tantalum or titanium) and (gate with (sidewall or (side adj wall)) with nitrid\$8) and ammonia	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/16 13:37
S7	407	S6 and temperature	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/16 13:42
S8	141	S7 and (nitridiz\$5 or nitrided or nitriding)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/16 13:42
S9	336	gate and nitride and (tungsten or tantalum or titanium) and (gate with (sidewall or (side adj wall)) with nitrid\$8) and ammonia	USPAT	OR	ON	2004/12/16 13:41
S10	561	gate and nitride and (tungsten or tantalum or titanium) and (gate with (sidewall or (side adj wall)) with nitrid\$8) and ammonia	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/16 13:41
S11	486	S10 and temperature	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/16 13:42

S12	150	S11 and ((nitridiz\$5 or nitrided or nitriding)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/16 15:52
S13	40	S12 and ((nitridiz\$5 or nitrided or nitriding) with temperature)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/17 17:15
S14	2	((("6284634") or ("6197702")).PN.	USPAT	OR	OFF	2004/12/17 19:04
S15	22581	substrate and gate and ((gate adj oxide) or (gate adj insulator) or (gate adj insulating)) and (gate adj electrode)	USPAT	OR	ON	2004/12/17 19:11
S16	0	S15 and ((carbonizing) with (sidewall or (side adj wall)))	USPAT	OR	ON	2004/12/17 19:12
S17	7	(carbonizing with (sidewall or (side adj wall)))	USPAT	OR	ON	2004/12/17 19:12
S18	17	(sidewall or (side adj wall)) with (carbonized or carbonised or carbonizing or carbonising)	USPAT	OR	ON	2004/12/17 19:13
S19	2002	(sidewall or (side adj wall)) with (carbon\$5)	USPAT	OR	ON	2004/12/17 19:14
S20	133	S19 and (gate adj electrode)	USPAT	OR	ON	2004/12/17 19:17
S21	4	S20 and carbonized	USPAT	OR	ON	2004/12/17 19:17
S22	219	(carbonizing or carbonided or carbonized or carbonised) and (carbon with gas) and ((sidewall or (side adj wall)) or (gate adj electrode))	USPAT	OR	ON	2004/12/20 17:00
S23	0	methane with carbonize with sidewall	USPAT	OR	ON	2004/12/20 17:00
S24	20	methane and carbonize and sidewall	USPAT	OR	ON	2004/12/20 17:01
S25	244	(silicon adj carbide) with (sidewall or (side adj wall))	USPAT	OR	ON	2004/12/20 17:04
S26	18	S25 and methane	USPAT	OR	ON	2004/12/20 17:17
S27	1957	(gate adj electrode) and (polycrystalline adj silicon) and (metal adj silicide)	USPAT	OR	ON	2004/12/20 18:20
S28	540	S27 and (titanium adj silicide)	USPAT	OR	ON	2004/12/20 18:23
S29	263	(metal adj silicide).ti.	USPAT	OR	ON	2004/12/20 18:24
S30	84	S29 and (polycrystalline adj silicon)	USPAT	OR	ON	2004/12/20 18:41
S31	2	S30 and nitriding	USPAT	OR	ON	2004/12/20 18:24

S32	72	(gate adj electrode) with undercutting	USPAT	OR	ON	2004/12/20 18:41
S33	1542	438/197.ccls. or 438/585.ccls. or 438/652.ccls.	USPAT	OR	ON	2004/12/21 15:16
S34	1751	438/655.ccls. or 438/660.ccls. or 438/664.ccls. or 438/682.ccls.	USPAT	OR	ON	2004/12/21 15:12
S35	1806	438/684.ccls. or 438/758.ccls. or 438/778.ccls. or 438/787.ccls.	USPAT	OR	ON	2004/12/21 15:12
S36	309	438/791.ccls.	USPAT	OR	ON	2004/12/21 16:48
S37	134	(semiconductor adj substrate) and (gate adj electrode) and (oxidizing with plasma)	USPAT	OR	ON	2004/12/21 15:50
S38	63	(damage with restor\$5) and (gate adj electrode) and ((insulation or insulator or insulating) adj film)	USPAT	OR	ON	2004/12/21 16:51
S39	2	((damage with restor\$5) with oxidizing) and (gate adj electrode)	USPAT	OR	ON	2004/12/21 16:52
S40	3	((damage with restor\$5) with oxidizing)	USPAT	OR	ON	2004/12/21 16:52